PRECITEC

Optical Sensor - *CHRocodile IT*

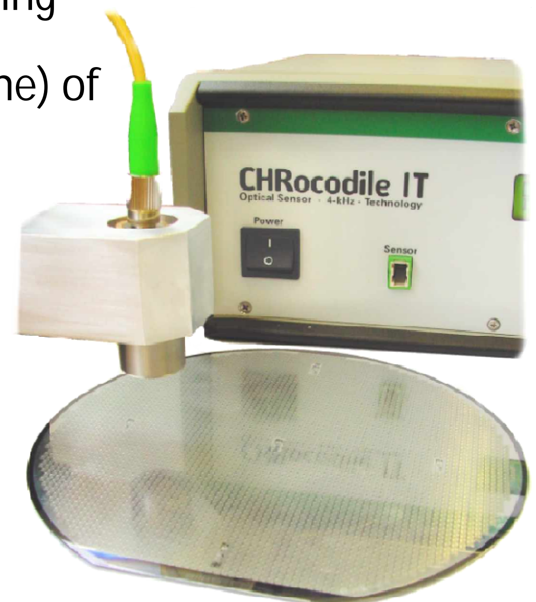
Non-contact measurement of Wafers, Solar Cells and Modules

Original | 3D – Topography

Thickness – Scan

Possible Applications

- Inline wafer thickness measurement *during* grinding
- Non-contact thickness measurement (inline/offline) of
  - § solar cells and solar modules
  - § transparent coatings and foils
- Measurement of multilayer systems
- Surface topography
- Measurement on hot & cold materials



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Features

- High measuring rate: 4 kHz
- High accuracy: up to 0.25 µm *
- z-resolution: up to 50 nm *
- Lateral resolution: 6.5 µm
- Si-thickness from 7 µm up to 1 mm
- Measurement also of GaAs
- Transparent coatings/foils from 17 µm up to 2.3 mm
- Robust measuring head without electronics or light source

*depends on used measuring range

The new *CHRocodile IT* of Precitec Optronik performs high-precision, non-contact distance and layer thickness measurements on wafers, solar cells and modules. With a single measuring head, it is capable of measuring up to 1mm thick silicon. Measurements can also be taken on other common infrared transparent materials, such as GaAs.

The basis for this new, nondestructive measuring method is an interferometric sensor which examines the substrate with infrared light. The *CHRocodile IT* is designed for simple and direct integration into the production process. However, it also serves as an economic and precise measuring tool for laboratory use.

Further Information:
www.CHRocodile.de

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